

# HQ:NSC15/No Al

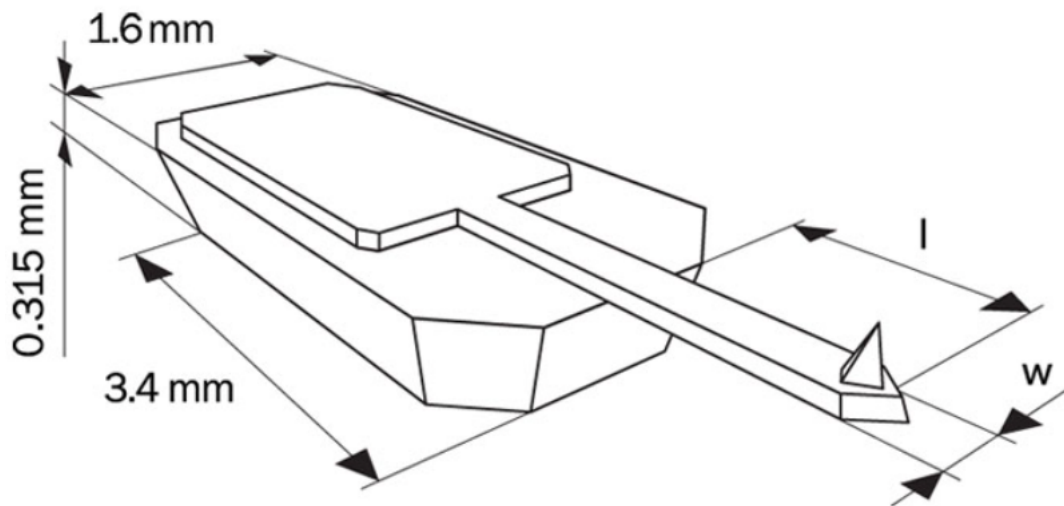
## Standard Tapping Mode AFM Probe

AFM probes of the HQ:NSC15 series are generally used in tapping mode for imaging hard samples when high topographic and phase contrast are necessary. These AFM probes are also suitable for non-contact mode.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

### Coating

none



### AFM Probe Specifications

#### AFM Tip

SHAPE	HEIGHT	FULL CONE ANGLE	RADIUS
Rotated	15 $\mu\text{m}$ (12 – 18 $\mu\text{m}$ )*	40°	< 8 nm

#### AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	40 N/m (20 – 80 N/m)*	325 kHz (265 – 410 kHz)*	125 $\mu\text{m}$ (1 – 130 $\mu\text{m}$ )*	30 $\mu\text{m}$ (27 – 33 $\mu\text{m}$ )*	4 $\mu\text{m}$ (3.5 – 4.5 $\mu\text{m}$ )*

\* typical values